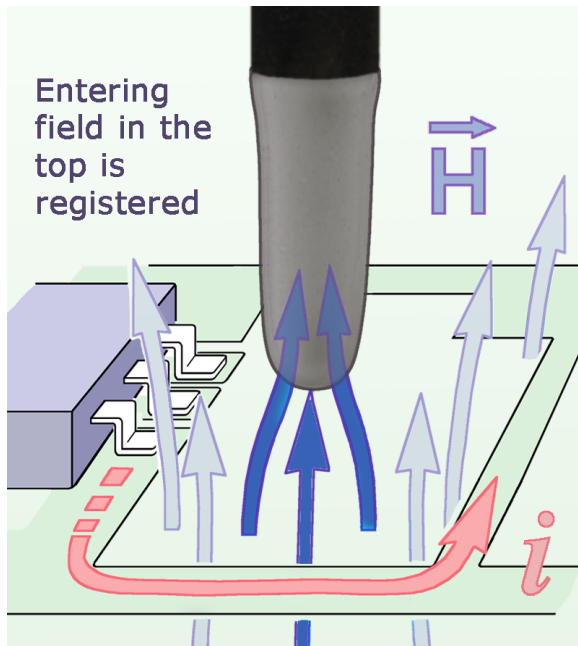


# XF-B 3-1

磁场探头 (30MHz-6GHz)



## Short description

XF-B 3-1型磁场探头的测量线圈相对垂直于探头柄。当探头竖直放置到电路板上时，其测量线圈直接平放在电路板的表面上。由此就能够测量到印刷电路板表面上很难达到的一些位置，如开关调节器的大元件之间的位置。

The XF-B 3-1 is a passive near-field probe which detects magnetic field lines emitted from the measured object at 90°. Magnetic field lines which enter the probe laterally are not detected.

In contrast to the XF-R 3-1 H-field probe, its coil is positioned in the probe tip at a 90° angle.

The near-field probe is small and handy. It has a current attenuating sheath and, therefore, is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The H-field probe has an internal terminating resistance.

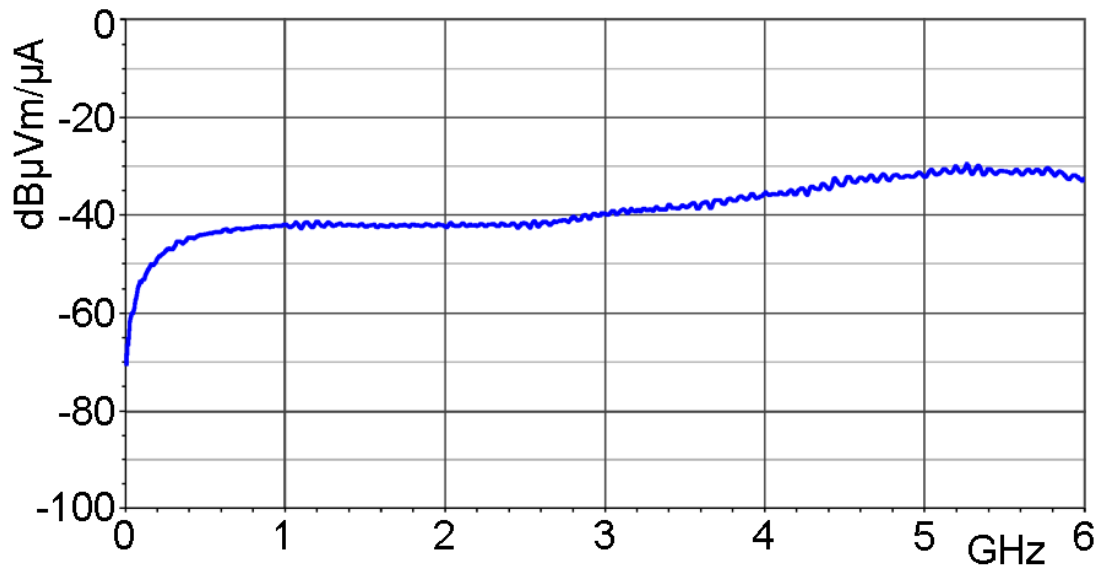
## Technical parameters

频率范围	30 MHz ... 6 GHz
分辨率	≈ 2 mm
探头尺寸	Ø ≈ 4 mm
输出接口	SMA, female, jack
重量	15 g

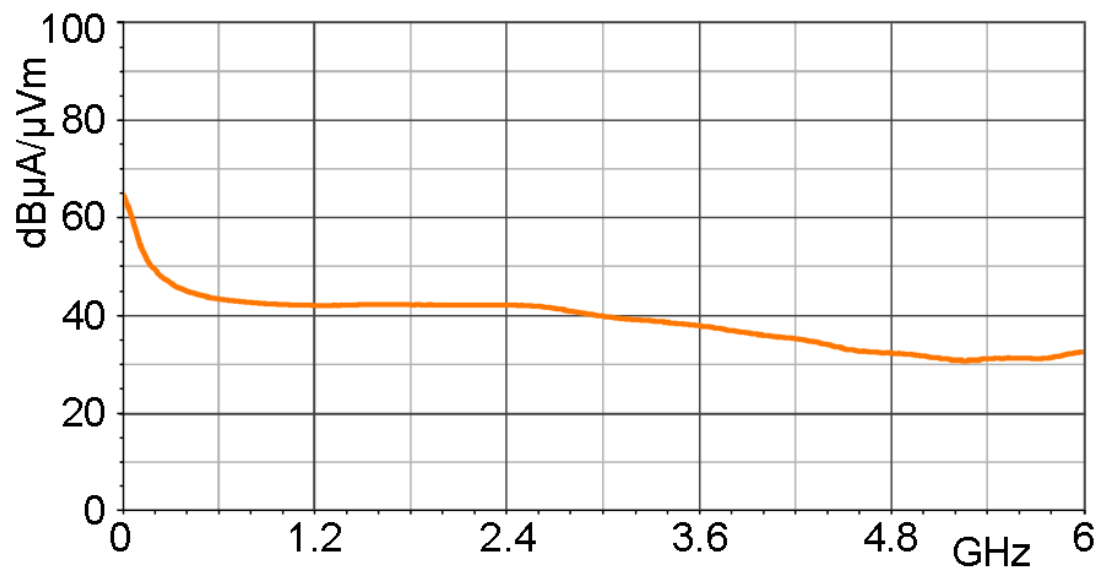
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频率特性 [dB $\mu$ V] / [dB $\mu$ A/m]



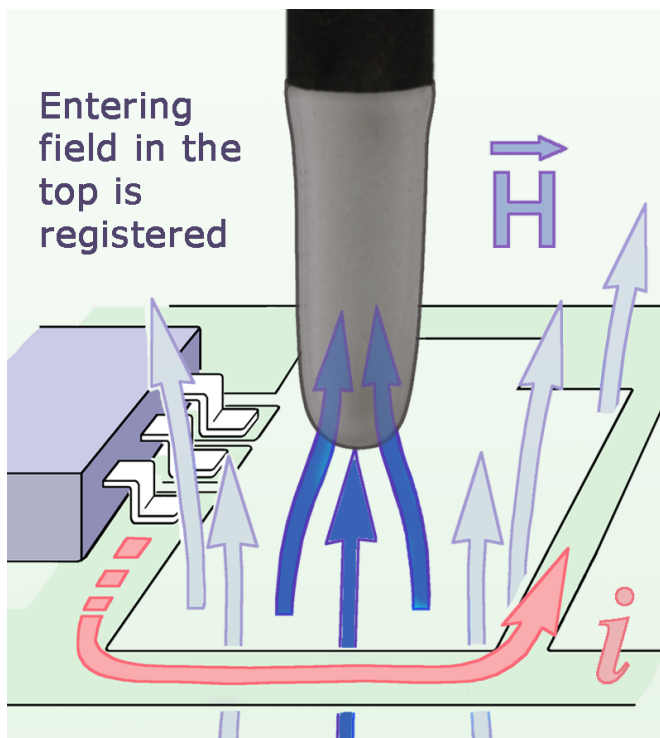
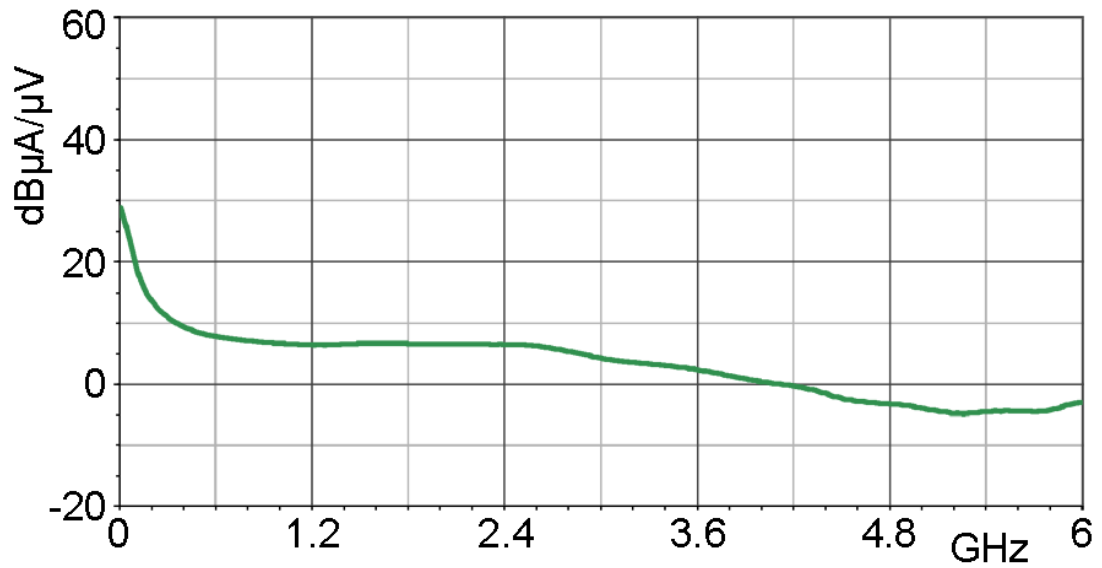
磁场校正曲线 [dB $\mu$ A/m] / [dB $\mu$ V]



# XF-B 3-1

磁场探头 (30MHz-6GHz)

电流校正曲线 [dB $\mu$ A] / [dB $\mu$ V]



# XF-B 3-1

磁场探头 (30MHz-6Hz)

**LANGER**  
EMV-Technik

Probe head

